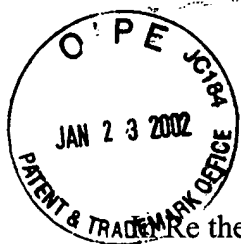


BEST AVAILABLE COPY

2881



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re the Application of:

MIRKIN et al.

Serial No.: 09/866,533

Filed: May 24, 2001

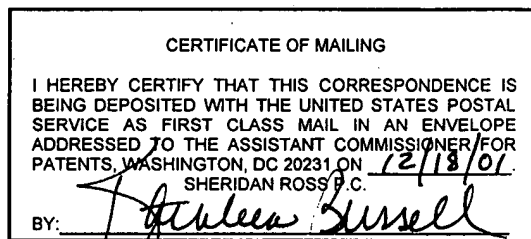
Atty. File No.: 4183-1-1

For: "METHODS UTILIZING SCANNING
PROBE MICROSCOPE TIPS AND
PRODUCTS THEREFOR OR
PRODUCED THEREBY"

Group Art Unit:

Examiner:

SUPPLEMENTAL INFORMATION
DISCLOSURE STATEMENT



Pursuant to Applicants' duty of disclosure under 37 CFR § 1.56 and 37 CFR §§ 1.97-1.98, Applicants hereby submit this Supplemental Information Disclosure Statement with a copy of the documents identified on the enclosed PTO Form 1449. All of the documents identified herein have been submitted in U.S. Patent Application Serial No. 09/477,997, and since the present patent application is a continuation-in-part thereof, copies of these documents are not being submitted under 37 CFR § 1.98(d). Applicants do not admit that any of the listed documents, alone or in any combination, are considered to be material to patentability as defined in 37 CFR § 1.56(b). Moreover, the inclusion of these documents is not to be construed as an admission by Applicants that each such document is prior art as to the above-identified patent application.

Respectfully submitted,

SHERIDAN ROSS P.C.

RECEIVED
APR 22 2002
TC 1700

By: Wannell M. Crook
Wannell M. Crook
Registration No. 31,071
1560 Broadway, Suite 1200
Denver, CO 80202-5141
(303) 863-9700

Date: Dec. 18, 2001

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 4183-1-1	SERIAL NO. 09/866,533
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		
APPLICANT MIRKIN et al.		GROUP ART
FILING DATE May 24, 2001		



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROP.
	1	5,747,334	5/5/98	Kay et al.	435	320.1	
	2	5,962,736	10/5/99	Zambias et al.	564	152	
	3	5,985,356	11/16/99	Schultz et al.	427	8	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
							YES	NO
	4	WO 96/31625	10/10/96	PCT				
	5	WO 99/31267	6/24/99	PCT				
	6	WO 00/36136	6/22/00	PCT				
	7	WO 00/46406	8/10/00	PCT				

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

8	Abbott et al., <i>Science</i> , 257:1380-1382 (1992)
9	C&EN: Letters, http://cen.acs.org/isubscribe/journals/...right.cgi?7931left.html/QueryZIP/mirkin , (C&EN, 79(31):8-11, 7/30/01)
10	Delamarche et al., <i>J. Phys. Chem. B</i> , 101:9263-9269 (1997)
11	Lutwyche et al., <i>Sensors and Actuators</i> , 73:89-94 (1999)
12	Minne et al., <i>Appl. Phys. Lett.</i> , 72(18):2340-2342 (1998)
13	Minne et al., <i>Appl. Phys. Lett.</i> , 73(12):1742-1744 (1998)
14	Hamilton, <i>New Times</i> , http://www.newtimesslo.com/archives/index.html and http://www.newtimesslo.com/archives/cov_stories_2001/cov_08162001.html (<i>New Times</i> , Vol. 16, No. 1, 8/16/01)
15	Ritter, <i>C&EN</i> , pp. 24-31, (11/12/2001)
16	Schwartz, <i>Langmuir</i> , 17:5971 (2001)
17	Tsukamoto et al., <i>Rev. Sci. Instrum.</i> , 62(7):1767-1771 (1991)
18	Vettiger et al., <i>Microelectronic Engineering</i> , 46:11-17 (1999)

RECEIVED
 APR 22 2002
 TC 1700

EXAMINER	DATE CONSIDERED
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	